

THE E-SLICE METHOD – IMPROVING THE THIN SLICE METHOD FOR LAR TPC'S

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ProtoDUNE Hadron Analysis Meeting

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Introduction

- ProtoDUNE beam particles are affected by space charge distortions
- XS calculations with the geometrical thin slice method are affected
 - [*Tingjun's study of the Thin Slice Method cuts away the first 80 wires \(~100MeV\) due to spatial distortions*](#)
- The E-Slice Method works in the energy phase space and thus avoids introducing the spatial distortions in the XS measurement
- Studies are based on Jakes PDSP_Analyzer ntuple
- TODAY MC true variables on full Prod4 sample
- The Method was developed at CERN by Francesco Pietropaolo, Stefania Bordoni and myself
 - *Thanks to Jake Calcutt and Kendall Mahn for fruitful discussions and help for validating the method*

Thin Slice \rightarrow E-Slice Derivation

- Probability of Pion interacting within a slab
 - $P_{interaction} = \sigma n dx$
- Change of N_π after going through a slab is initial number of pions multiplied by interaction Probability
 - $dN_\pi = -N_\pi \sigma n dx$
- Interested in pion loss dN_π after interaction wrt to deposited energy dE
 - *Using precise knowledge of dE/dx we can do the following*
 - $\frac{dN_\pi}{dE} = \frac{dN_\pi}{dx} \frac{dx}{dE} = -N_\pi \sigma \rho \frac{N_A}{A} \left(\frac{dE}{dx}\right)^{-1}$
- Measurement of any XS is done as function of kinetic energy, $d \rightarrow \Delta$
 - $\frac{\Delta N_\pi}{\Delta E} = N_\pi \sigma \rho \frac{N_A}{A} \left(\frac{dE}{dx}\right)^{-1}$
- The number of interacting pions is now in ΔN_π for the deposited energy ΔE

Thin Slice → E-Slice Derivation

- Measurement of any XS is done as function of kinetic energy, $d \rightarrow \Delta$

$$- \frac{\Delta N_{\pi}}{\Delta E} = N_{\pi} \sigma \rho \frac{N_A}{A} \left(\frac{dE}{dx} \right)^{-1}$$

- The number of interacting pions is now in ΔN_{π} for the deposited energy ΔE
 - *The classic thin slice introduces the wire pitch through associating ΔE with energy deposited per slab*
 - *BUT we don't have to use the slab thickness (affected by SCE, uncertainty!) at all, we can just remain in the energy phase space*
 - ΔE is just the **energy bin** in which we measure 😊

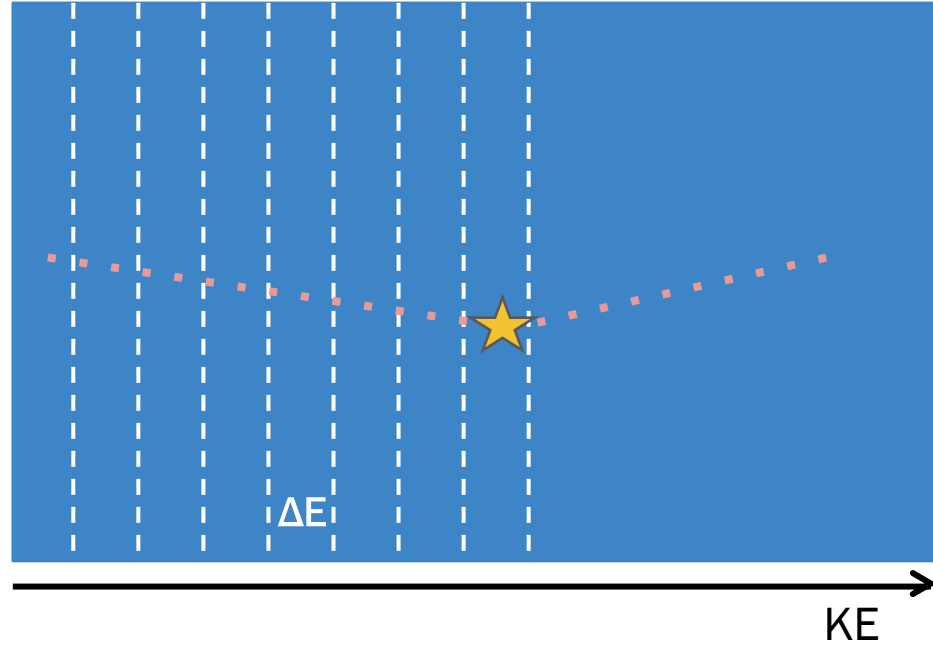
- The XS is measured as

$$\sigma(E_i) = \underbrace{\frac{A}{N_A \rho \Delta E}}_{\text{Constant}} \underbrace{\frac{dE}{dx}(E_i)}_{\text{Mean Energy Loss at Bin Energy } E_i \text{ from Bethe Bloch}} \underbrace{\frac{N_{\pi \text{Interacting}}(E_i)}{N_{\pi \text{Incident}}(E_i)}}_{\text{Ratio of Int and Inc Histogram}}$$

Constant * **Mean Energy Loss at Bin Energy E_i from Bethe Bloch** * **Ratio of Int and Inc Histogram**

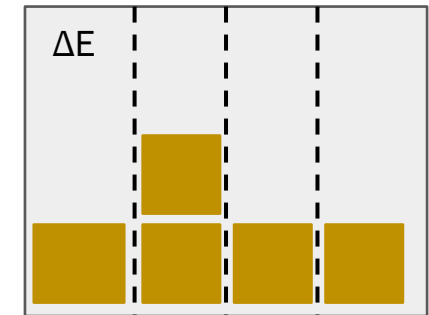
Thin Slice → E-Slice Derivation

Jake Calcutt

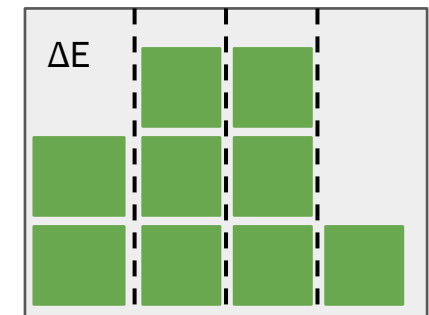


$$\sigma(E_i) = \frac{A}{N_A \rho \Delta E} \frac{dE}{dx}(E_i) \frac{N_{\pi \text{Interacting}}(E_i)}{N_{\pi \text{Incident}}(E_i)}$$

$\sigma \sim$



Interacting



Incident

Assumptions

- The E-slice thickness is chosen to be **constant**
 - *Each slice can be considered as an independent experiment*
 - *If low statistics (for lowE for example) E-slice thickness can be varied*
- We define each slice to have 20 MeV
 - *The E-slice thickness is mostly insensitive to SCE (because recombination for beam particles varies little in beam region, lucky! → See Backup!)*
- If a pion interaction occurs at slice i , it must have gone through all the previous slices
- All pions have the same energy when reaching a particular slice
 - *Smearing only from Beam momentum and uncertainty in Beam plug E loss*
- Pion energy in each E slice is a slice property and can be derived on event-by-event basis
- dE_{dx} can be derived using the bethe bloch formula for the mean energy loss at the corresponding pion kinetic energy
 - *dE_{dx} vs range (PID) is excellent for ProtoDUNE → [Performance Paper](#)*

Validation with MC Prod4

- Using
 - `/dune/data/users/fstocker/ANALYSIS/prod4_files/pionana_Prod4_mc_1GeV_1_14_21.root`
 - *Full Prod4 MC*
- True Interactions "pi+Inelastic"
 - *Absorption = Inelastic with no pions in the final state*
 - *Charge exchange = Inelastic with no π^\pm and $1\pi^0$ in the final state*
 - *Total Inelastic*
- True kinetic energy
 - *Initial*
 - *At interaction*

E slice – Validation in MC true Prod4

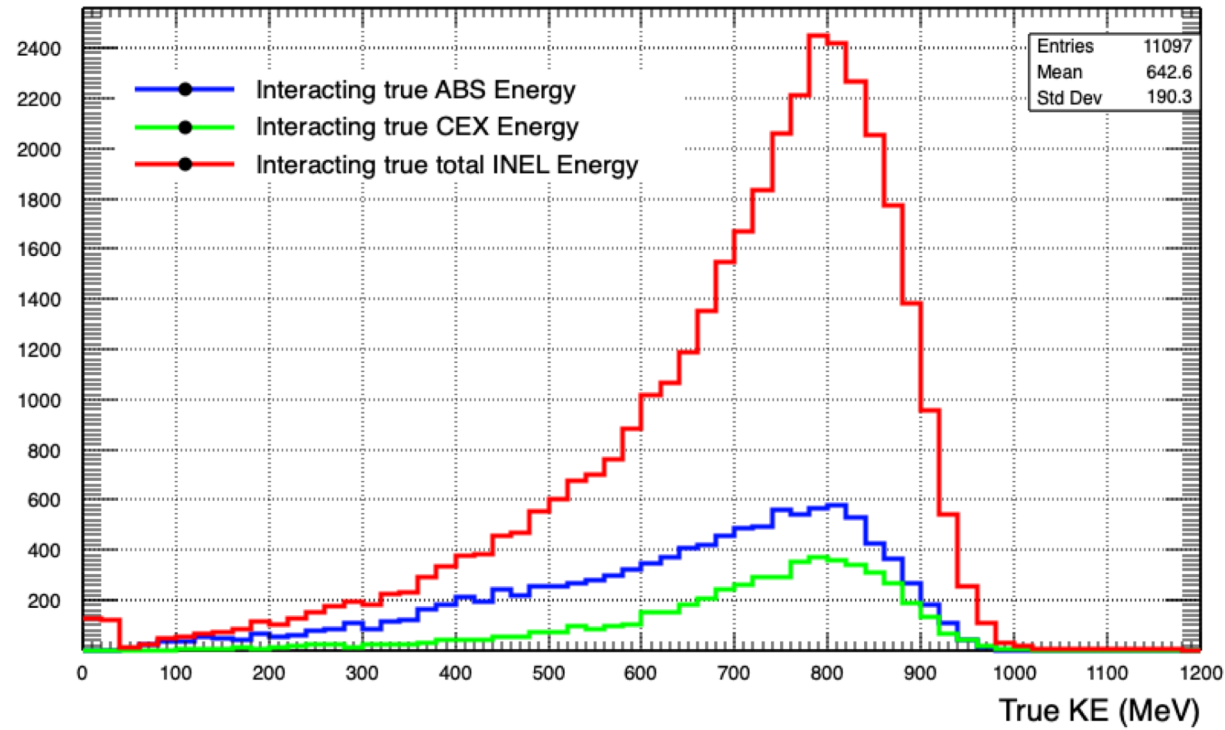
- E Slice thickness is constant
- E Slice thickness is calculated using Energy deposition information in the calorimetry data product
 - *Reminder: need to see how this is done in reco*
- Beam particles pass through a region where Efield variation from nominal is small and recombination variation negligible --> see Backup
 - *SCE corrections are not needed*

Incident and Interacting Histograms – MC true Prod4

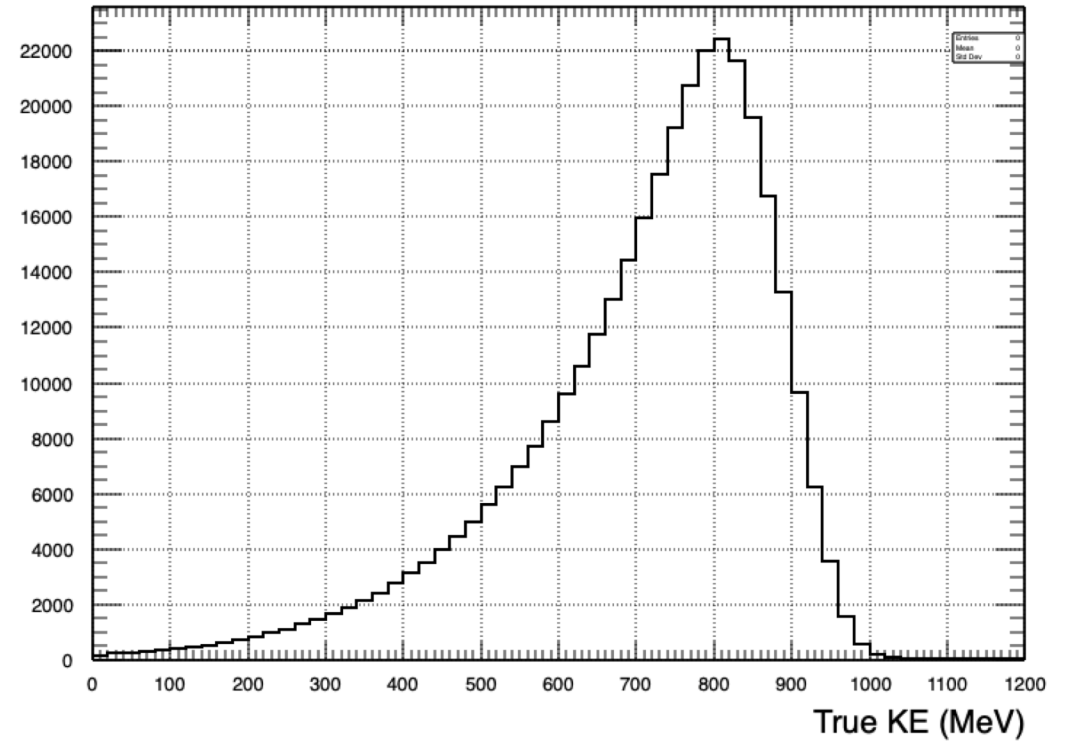
- Select true pion events
- For pions with “pi+inelastic” find true initial KE and KE at interaction point
 - “*true_beam_incidentEnergies[0]*”
 - Work in Progress, the first incident KE bin is not uniformly filled, can be easily taken care of with weights (ToDo)
 - “*true_beam_endP*” → *convert to KE*
 - There are some issues with *true_beam_interactingEnergy* (sim IDE, slicing Jake)
- Add an entry in incident histogram for each energy bin from initial KE to interacting KE, for each pion
- Interacting histogram receives an entry for the interacting KE, for each pion

Interacting and Incident

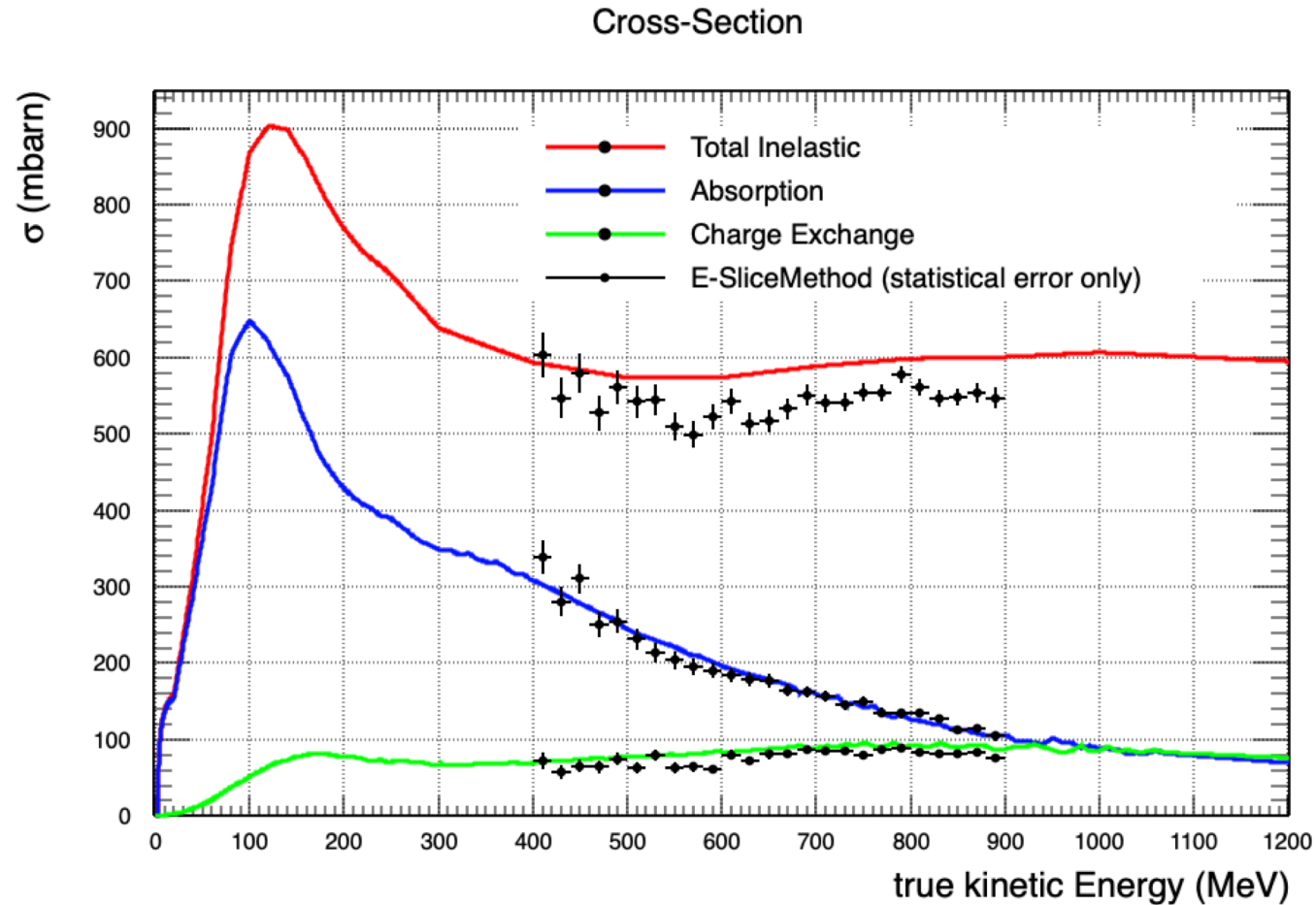
Interacting Histograms nostack



Incident True Pion



Cross Section

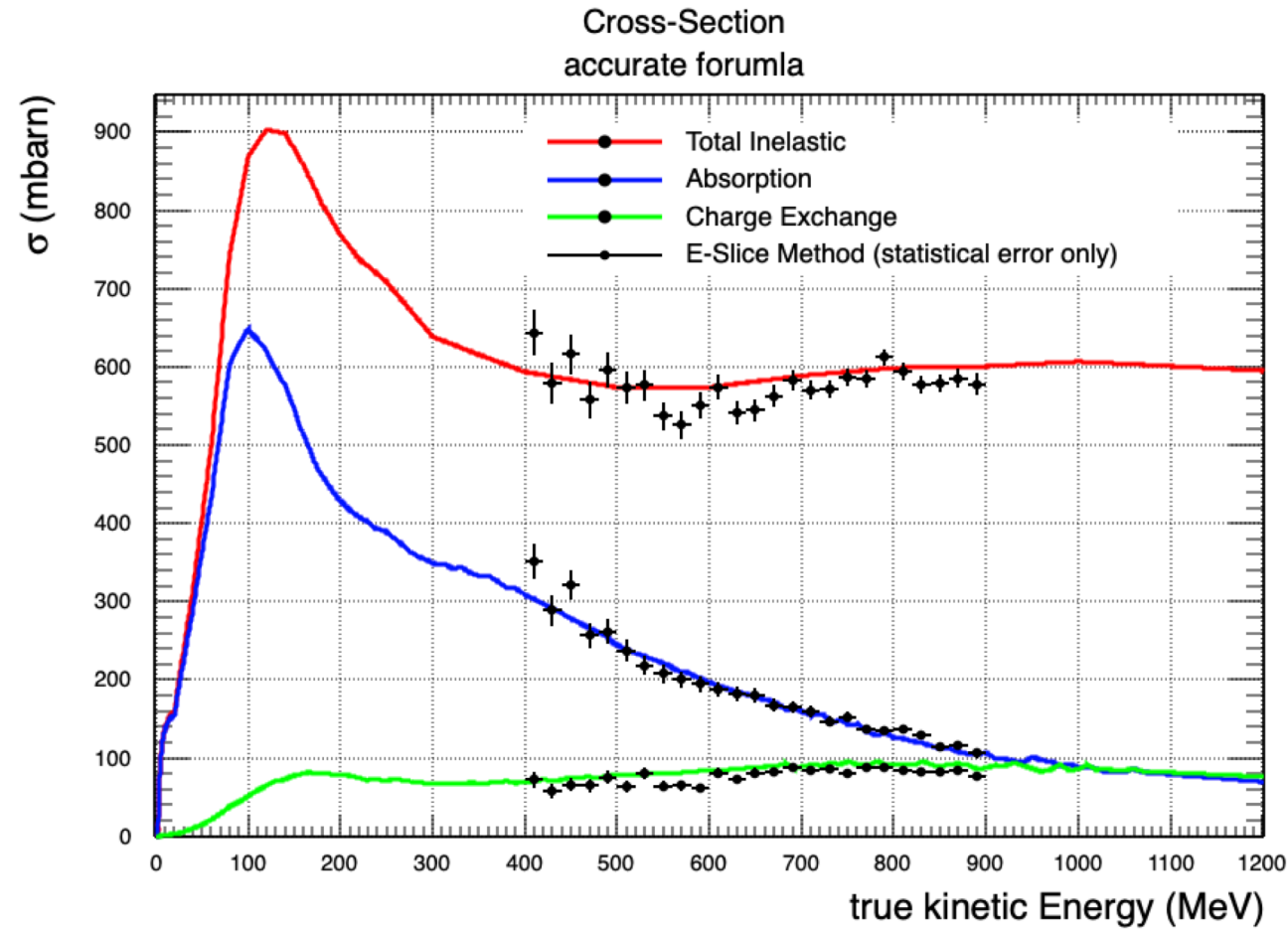


- Same discrepancy at inelastic for high KE as Tingjun saw because of $N_{int} \ll N_{inc}$
- Use in that case

$$\sigma(E_i) = \frac{A}{N_A \rho \Delta E} \frac{dE}{dx}(E_i) \log \left(\frac{N_{\pi Incident}(E_i)}{N_{\pi Incident}(E_i) - N_{\pi Interacting}(E_i)} \right)$$

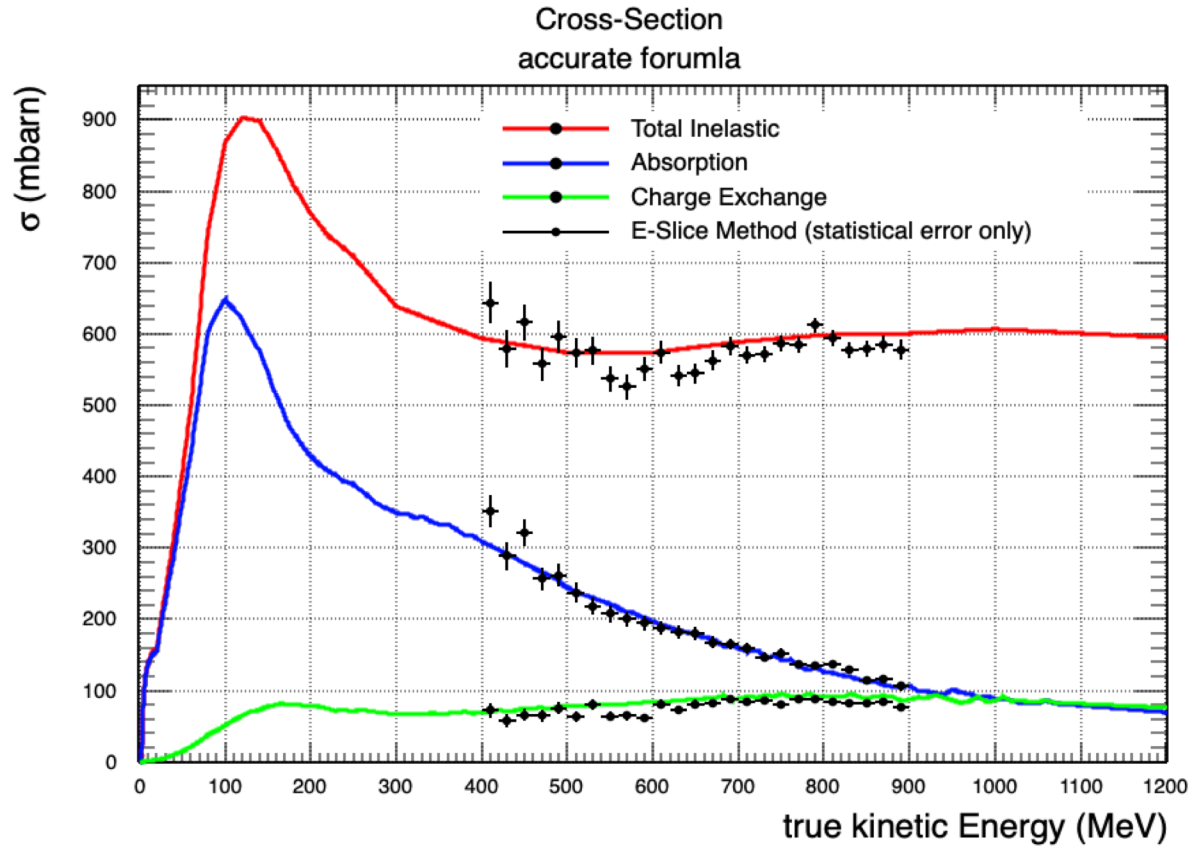
Cross Section accurate formula

$$\sigma(E_i) = \frac{A}{N_A \rho \Delta E} \frac{dE}{dx}(E_i) \log \left(\frac{N_{\pi \text{Incident}}(E_i)}{N_{\pi \text{Incident}}(E_i) - N_{\pi \text{Interacting}}(E_i)} \right)$$



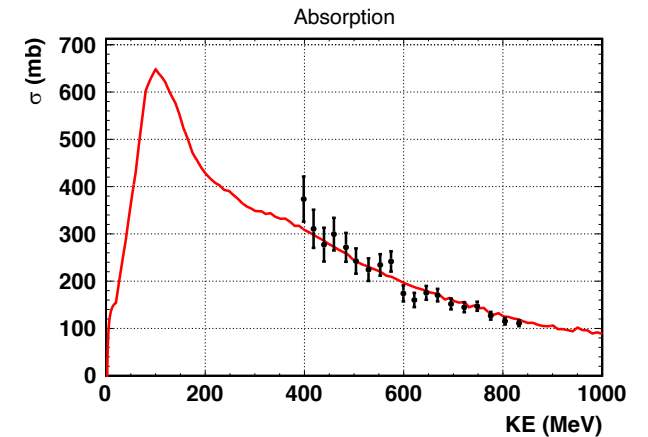
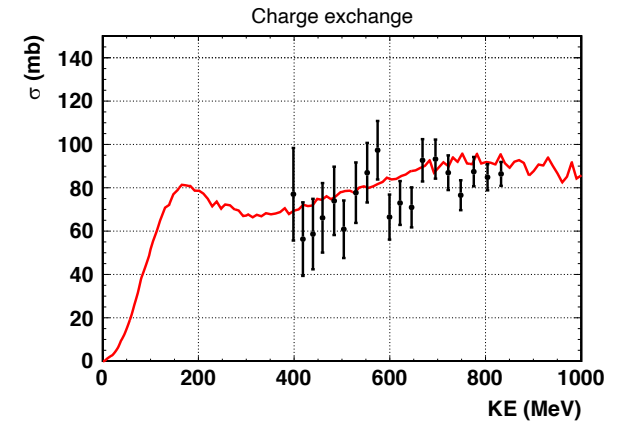
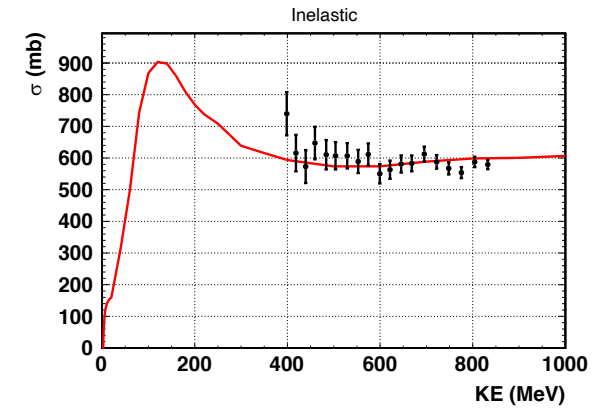
■ Better agreement for inelastic XS

E-Slice vs Thin Slice



- The E-Slice Method shows nice agreement with the GeantXS
- Can access higher energies than the thin slice method

Tingjun's study of thin slice method



Conclusions & Next Steps

- The E-Slice method can calculate and reproduce the GeantXS for true interactions and corresponding true KE
 - *The uncertainties due to SCE can be avoided by using energy slices*
- The E-Slice method is promising than the thin slice method for ProtoDUNE beam particles

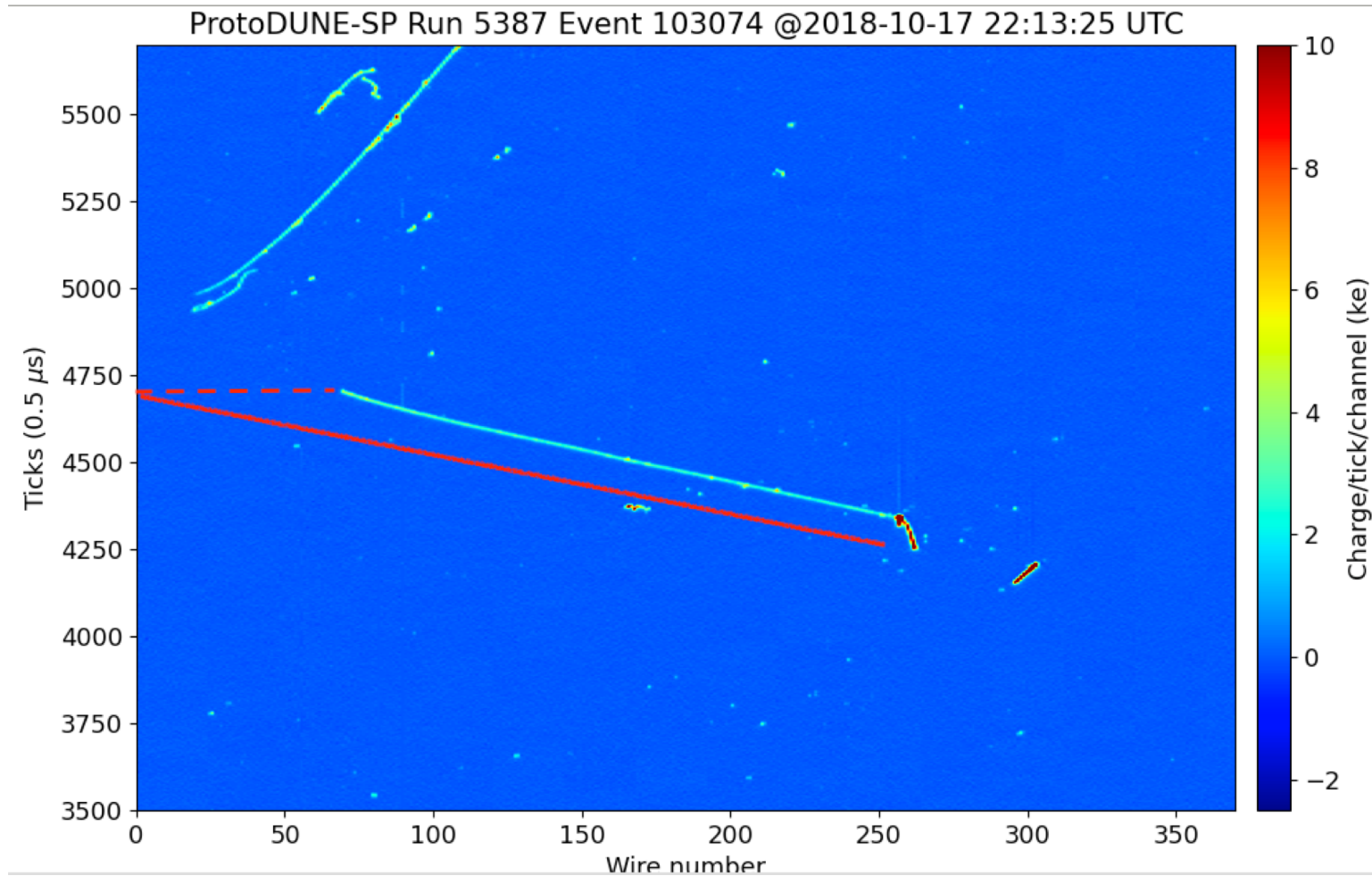
Next Steps

- Using reconstructed energy (MC and Data)
 - *Need to make sure that it is $dQ \rightarrow dE$ without SCE corrections*
 - Allows to extend range to higher KE without cutting away to first 80 wires (~100MeV) for example
 - *NOT $dE = dEdx * dx$ otherwise we might pull in SCE distortions (?)*

BACKUP



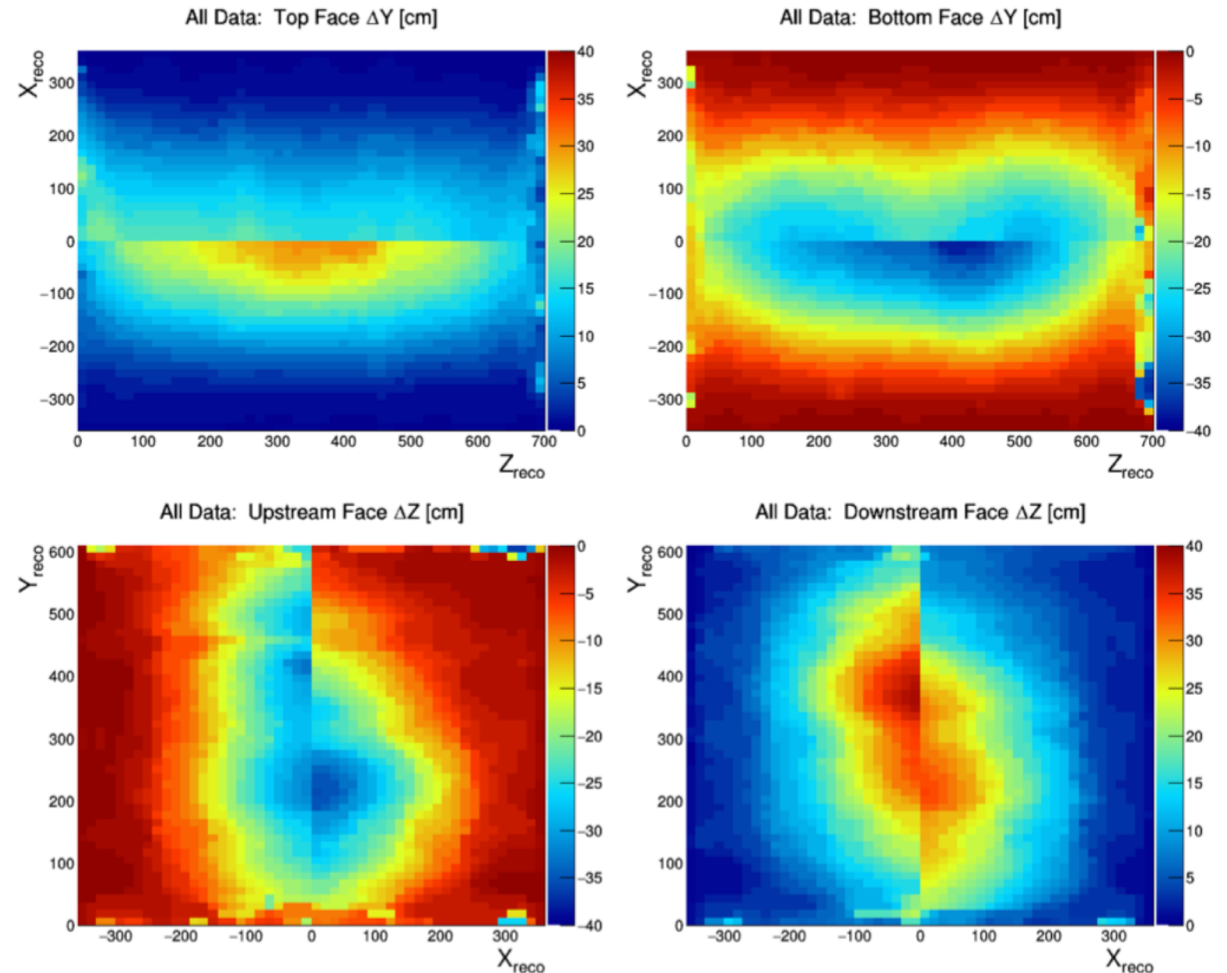
Test SCE correction with model independent approach for beam particles



- Using data a point by point correction can be found for beam particles

Recap SCE effect ProtoDUNE

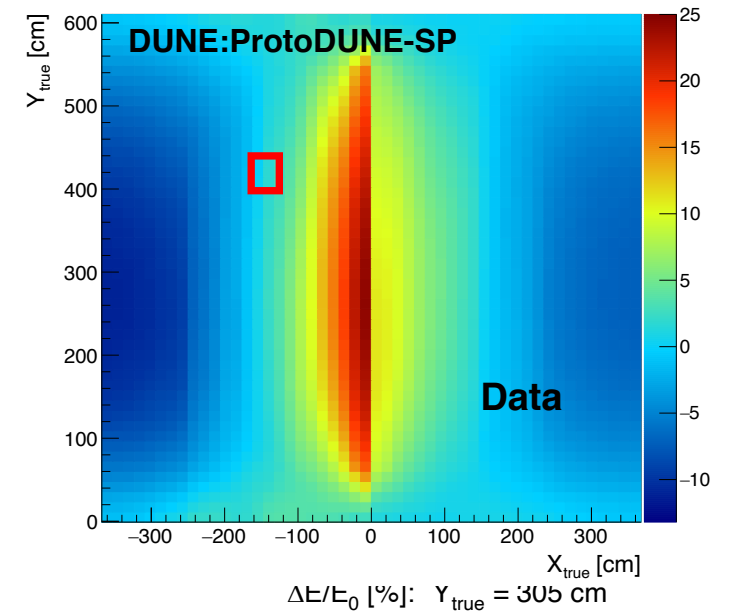
- SCE in ProtoDUNE causes displacement in X,Y,Z
- Plots show displacement in Y and Z from the detector top, bottom, front and back faces measured with cathode crossing cosmics
- The SCE effect is modeled with these plots using interpolation between the faces
- SCE corrections are based on this work so far



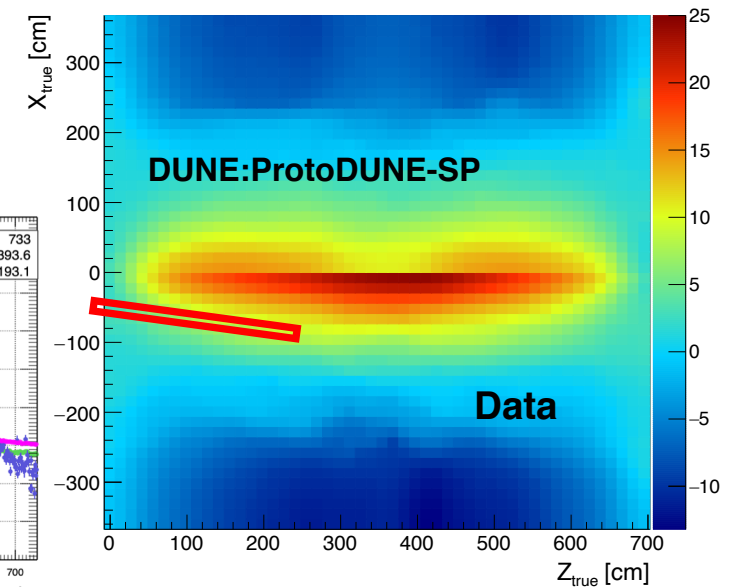
Effect of Recombination

- Efield maps in beam particle region can be trusted as SCE effect reproduces in general the data-corrected pitch
- There is no major effect to be considered from recombination on the proposed method as long as we just use beam particles

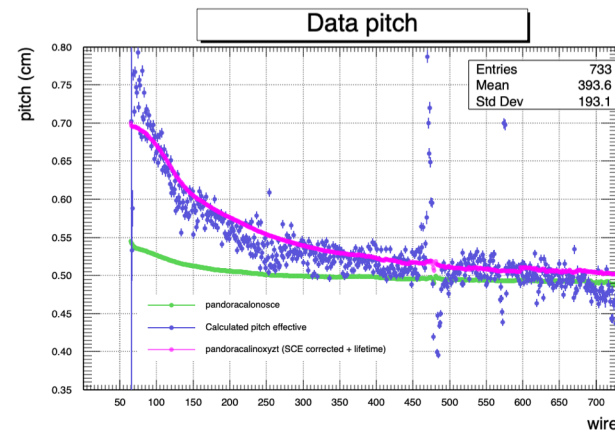
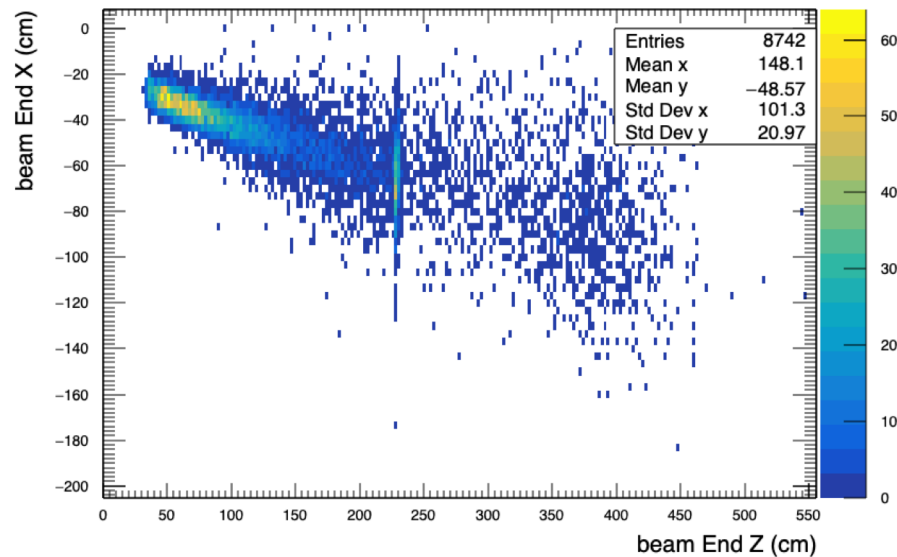
$\Delta E/E_0$ [%]: $Z_{\text{true}} = 347$ cm



$\Delta E/E_0$ [%]: $Y_{\text{true}} = 305$ cm

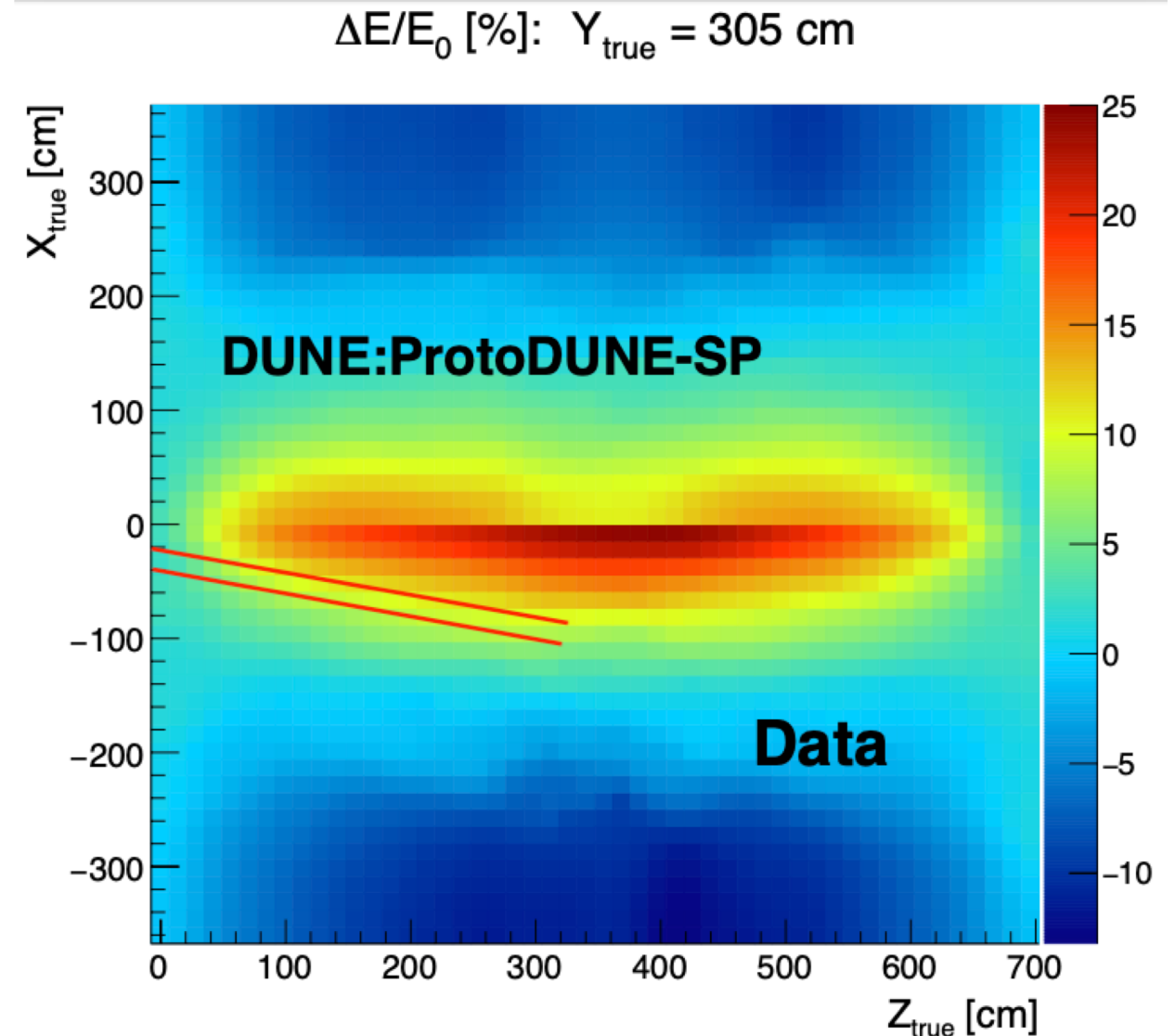


Beam End Position X,Z Data 5387

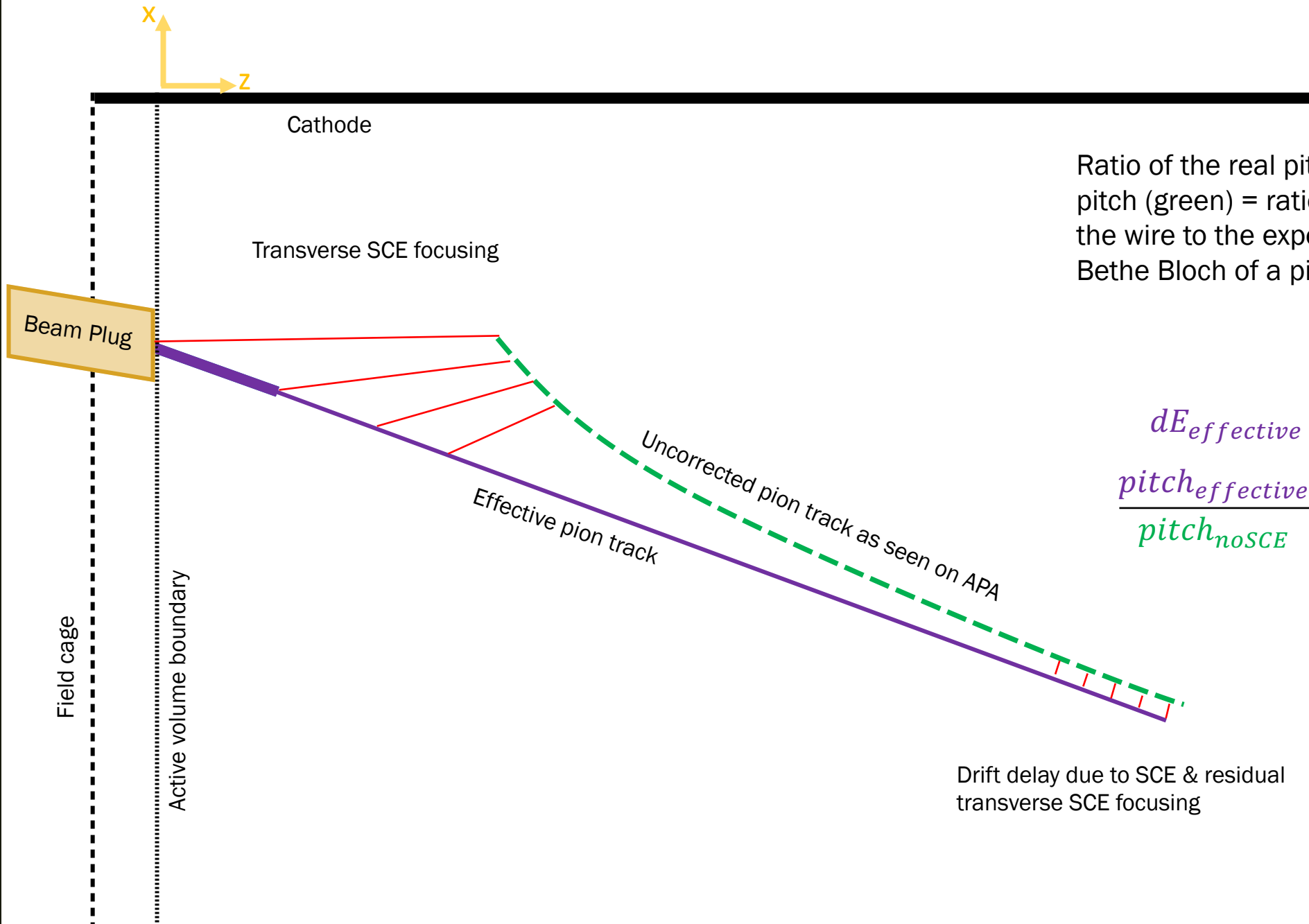


Effect of Recombination

- Efield changes maximally 10%
→ 550kv/cm
- Recombination at 500kv/cm = 0.698
- Recombination at 550kv/cm = 0.706
- Change of 1.2% (maximal)
- Uncertainties due to recombination are much smaller than 1%



Idea of the method



Ratio of the real pitch (purple) to the apparent pitch (green) = ratio of $dEdx$ (MPV) recorded on the wire to the expected $dEdx$ (MPV) from Bethe Bloch of a pion at given kinetic energy

$$dE_{effective} = dE_{noSCE+lifetime}$$

$$\frac{pitch_{effective}}{pitch_{noSCE}} = \frac{dEdx_{noSCE+lifetime}}{dEdx_{expected}}$$

Drift delay due to SCE & residual transverse SCE focusing

ProtoDUNE

